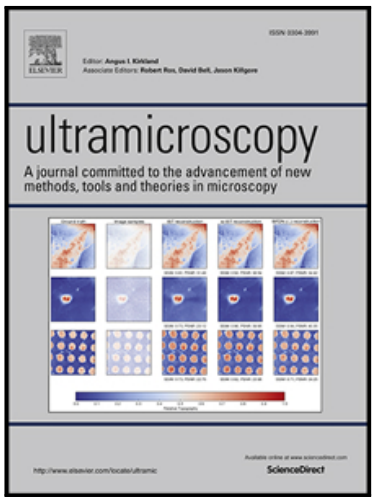

MS-STEM-FEM: A Parallelized Multi-slice Fluctuation TEM Simulation Tool

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Highlights

- Simulation of experimental technique quantifying order in glassy materials
- Multislice method incorporating microscope parameters and complex wave propagation
- Dynamical diffraction has less influence than the variety of crystallite orientations
- Linear performance scaling with respect to model thickness
- Comparison of several statistical measures